

**Search Notes**

Application/Control No.

10/775,284

Examiner

Patricia Leith

Applicant(s)/Patent under  
Reexamination

LEE, YUAN Y.

Art Unit

1655

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBACKFILE updated	2/27/2008	PL
Inventor name search updated EAST/PALM	2/27/2008	PL
STN: Indexed BIOSCIENCE & Napralert database (approx. 76 databases total)	2/27/2008	PL